

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs

- Dependable Texas Instruments Quality and Reliability

description

The '279 offers 4 basic \bar{S} - \bar{R} flip-flop latches in one 16-pin, 300-mil package. Under conventional operation, the \bar{S} - \bar{R} inputs are normally held high. When the \bar{S} input is pulsed low, the Q output will be set high. When \bar{R} is pulsed low, the Q output will be reset low. Normally, the \bar{S} - \bar{R} inputs should not be taken low simultaneously. The Q output will be unpredictable in this condition.

FUNCTION TABLE
(each latch)

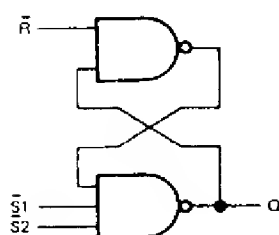
INPUTS		OUTPUT
\bar{S}^\dagger	\bar{R}	Q
H	H	Q_0
L	H	H
H	L	L
L	L	H^\ddagger

H = high level L = low level

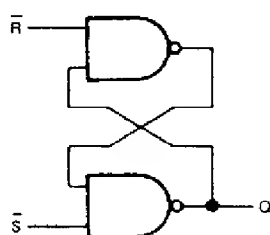
 † For latches with double S inputs: Q_0 = the level of Q before the indicated input conditions were established. ‡ This configuration is nonstable; that is, it may not persist when the \bar{S} and \bar{R} inputs return to their inactive (high) level.H = both \bar{S} inputs highL = one or both \bar{S} inputs low

logic diagram (positive logic)

(latches 1 and 3)



(latches 2 and 4)

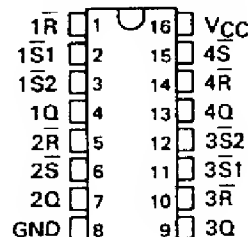


SN54279, SN54LS279A . . . J OR W PACKAGE

SN74279 . . . N PACKAGE

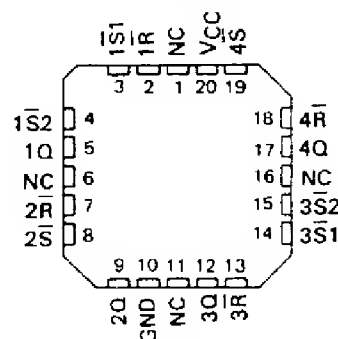
SN74LS279A . . . D OR N PACKAGE

(TOP VIEW)

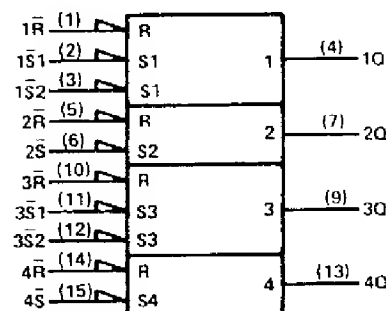


SN54LS279A . . . FK PACKAGE

(TOP VIEW)

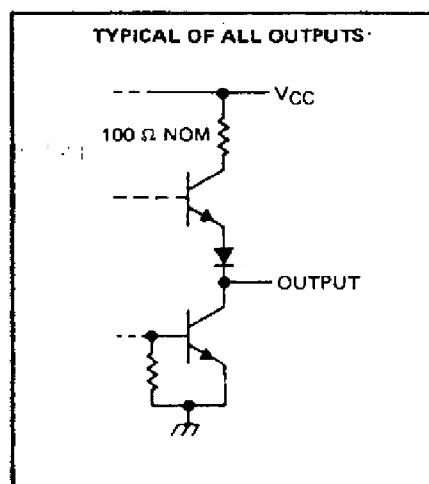


NC - No internal connection

logic symbol[§][§]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

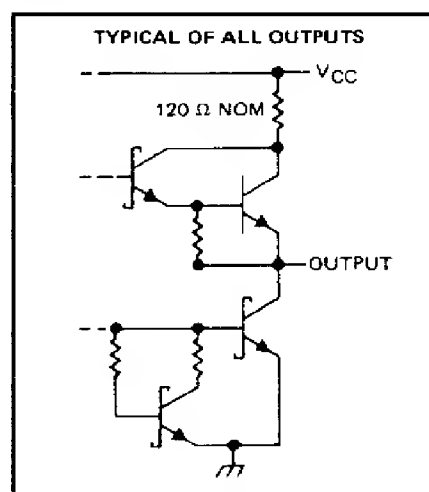
Pin numbers shown are for D, J, N, and W packages.

schematics of inputs and outputs



EQUIVALENT OF ALL INPUTS

\bar{R} INPUTS - $R_{eq} = 9 \text{ k } \Omega \text{ NOM}$
 \bar{S} INPUTS - $R_{eq} = 15 \text{ k } \Omega \text{ NOM}$



Supply voltage, V _{CC} (see Note 1)	7 V
Input voltage: '279	5.5 V
'LS279A	7 V
Operating free-air temperature range: SN54' TYPES	-55° C to 125° C
SN74' TYPES	0° C to 70° C
Storage temperature range	-65° C to 150° C

NOTE 1: Voltage values are with respect to network ground terminal.

SN54279, SN74279 QUADRUPLE S-R LATCHES

recommended operating conditions

	SN54279			SN74279			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.8			0.8	V
I _{OH} High-level output current			-0.8			-0.8	mA
I _{OL} Low-level output current			16			16	mA
t _w Pulse duration, low	20			20			ns
T _A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN54279			SN74279			UNIT
		MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V _{IK}	V _{CC} = MIN, I _I = -12 mA			-1.5			-1.5	V
V _{OH}	V _{CC} = MIN, V _{IL} = 0.8 V, I _{OH} = -0.8 mA	2.4	3.4		2.4	3.4		V
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 16 mA		0.2	0.4		0.2	0.4	V
I _I	V _{CC} = MAX, V _I = 5.5 V			1			1	mA
I _{IH}	V _{CC} = MAX, V _I = 2.4 V			40			40	µA
I _{IL}	V _{CC} = MAX, V _I = 0.4 V			-1.6			-1.6	mA
I _{OS} §	V _{CC} = MAX	-18		-55	-18		-57	mA
I _{CC}	V _{CC} = MAX, See Note 2		18	30		18	30	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time.

NOTE 2: I_{CC} is measured with all R inputs grounded, all S inputs at 4.5 V, and all outputs open.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	\bar{S}	Q	R _L = 400 Ω, C _L = 15 pF		12	22	ns
t _{PHL}	S	Q			9	15	
t _{PHL}	\bar{R}	Q			15	27	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

SN54LS279A, SN74LS279A **QUADRUPLE S-R LATCHES**

recommended operating conditions

	SN54LS279A			SN74LS279A			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.7			0.8	V
I _{OH} High-level output current			-0.4			-0.4	mA
I _{OL} Low-level output current			4			8	mA
t _w Pulse duration, low	20			20			ns
T _A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN54LS279A			SN74LS279A			UNIT
		MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V _{IK}	V _{CC} = MIN, I _I = -18 mA			-1.5			-1.5	V
V _{OH}	V _{CC} = MIN, V _{IL} = MAX, I _{OH} = -0.4 mA	2.5	3.4		2.7	3.4		V
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 4 mA		0.25	0.4		0.25	0.4	V
	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 8 mA					0.25	0.5	
I _I	V _{CC} = MAX, V _I = 7 V			0.1			0.1	mA
I _{IH}	V _{CC} = MAX, V _I = 2.7 V			20			20	µA
I _{IL}	V _{CC} = MAX, V _I = 0.4 V			-0.2			-0.2	mA
I _{OS} §	V _{CC} = MAX	-20		-100	-20		-100	mA
I _{CC}	V _{CC} = MAX, See note 2		3.8	7		3.8	7	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time, and the duration of the short-circuit should be less than one second.

NOTE 2: I_{CC} is measured with all R inputs grounded, all S inputs at 4.5 V, and all outputs open.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	S	Q	R _L = 2 kΩ, C _L = 15 pF	12	22	ns	
t _{PHL}				13	21		
t _{PHL}	R	Q		15	27		ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

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